

<b>Notice of References Cited</b>	Application/Control No. 10/802,649	Applicant(s)/Patent Under Reexamination KITAGAWA, HITOSHI	
	Examiner Kianni C. Kaveh	Art Unit 2883	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,882,782	04-2005	Conzone et al.	385/49
	B	US-2003/0174955	09-2003	Chen et al.	385/42
	C	US-6,836,598	12-2004	Chen et al.	385/42
	D	US-2003/0039461	02-2003	How Kee Chun et al.	385/140
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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	N					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	('Integrated-optical wavelength sensor with self-compensation of thermally induced phase shifts by use of a LiNbO3 unbalanced Mach-zehnder interferometer'; 10/10/2002/vol. 41, no. 29/Applied Optics; pages 6211-6219
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.